MM54HC573/MM74HC573

National Semiconductor

T-46-07-11

MM54HC573/MM74HC573 TRI-STATE® Octal D-Type Latch

General Description

These high speed octal D-type latches utilize advanced silicon-gate CMOS technology. They possess the high noise immunity and low power consumption of standard CMOS integrated circuits, as well as the ability to drive 15 LS-TTL loads. Due to the large output drive capability and the TRI-STATE feature, these devices are ideally suited for interfacing with bus lines in a bus organized system.

When the LATCH ENABLE(LE) input is high, the Q outputs will follow the D inputs. When the LATCH ENABLE goes low, data at the D inputs will be retained at the outputs until LATCH ENABLE returns high again. When a high logic level is applied to the OUTPUT CONTROL OC input, all outputs go to a high impedance state, regardless of what signals are present at the other inputs and the state of the storage elements.

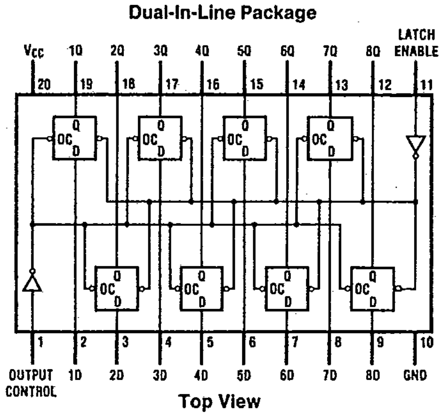
The 54HC/74HC logic family is speed, function and pinout compatible with the standard 54LS/74LS logic family. All inputs are protected from damage due to static discharge by internal diode clamps to V_{CC} and ground.

Features

- Typical propagation delay: 13 ns
- Wide operating voltage range: 2 to 6 volts
- Low input current: 1 μA maximum
- Low quiescent current: 80 μA maximum (74HC Series)
- Compatible with bus-oriented systems
- Output drive capability: 15 LS-TTL loads

Connection Diagram

Dual-In-Line Package



Top View

TL/F/5212–1

Order Number MM54HC573* or MM74HC573*

*Please look into Section 8, Appendix D for availability of various package types.

Truth Table

Output Control	Latch Enable	Data	Output
L	H	H	H
L	H	L	L
L	L	X	Q_0
H	X	X	Z

H = high level, L = low level

Q_0 = level of output before steady-state input conditions were established.

Z = high impedance

X = Don't care

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Absolute Maximum Ratings (Notes 1 & 2)

If Military/Aerospace specified devices are required, contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	-0.5 to $+7.0$V
DC Input Voltage (V_{IN})	-1.5 to $V_{CC}+1.5$V
DC Output Voltage (V_{OUT})	-0.5 to $V_{CC}+0.5$V
Clamp Diode Current (I_{IK}, I_{OK})	±20 mA
DC Output Current, per pin (I_{OUT})	±35 mA
DC V_{CC} or GND Current, per pin (I_{CC})	±70 mA
Storage Temperature Range (T_{STG})	−65°C to +150°C
Power Dissipation (P_D)	
(Note 3)	600 mW
S.O. Package only	500 mW
Lead Temperature (T_L)	
(Soldering 10 seconds)	260°C

Operating Conditions

	Min	Max	Units
Supply Voltage (V_{CC})	2	6	V
DC Input or Output Voltage (V_{IN}, V_{OUT})	0	V_{CC}	V
Operating Temp. Range (T_A)			
MM74HC	−40	+85	°C
MM54HC	−55	+125	°C
Input Rise or Fall Times (t_r, t_f) $V_{CC}=2.0$V		1000	ns
$V_{CC}=4.5$V		500	ns
$V_{CC}=6.0$V		400	ns

DC Electrical Characteristics (Note 4)

Symbol	Parameter	Conditions	V_{CC}	$T_A=25°C$		74HC $T_A=-40$ to 85°C	54HC $T_A=-55$ to 125°C	Units
				Typ	Guaranteed Limits			
V_{IH}	Minimum High Level Input Voltage		2.0V		1.5	1.5	1.5	V
			4.5V		3.15	3.15	3.15	V
			6.0V		4.2	4.2	4.2	V
V_{IL}	Maximum Low Level Input Voltage**		2.0V		0.5	0.5	0.5	V
			4.5V		1.35	1.35	1.35	V
			6.0V		1.8	1.8	1.8	V
V_{OH}	Minimum High Level Output Voltage	$V_{IN}=V_{IH}$ or V_{IL} $\|I_{OUT}\|\leq 20\ \mu A$	2.0V	2.0	1.9	1.9	1.9	V
			4.5V	4.5	4.4	4.4	4.4	V
			6.0V	6.0	5.9	5.9	5.9	V
		$V_{IN}=V_{IH}$ or V_{IL} $\|I_{OUT}\|\leq 6.0$ mA	4.5V	4.2	3.98	3.84	3.7	V
		$\|I_{OUT}\|\leq 7.8$ mA	6.0V	5.7	5.48	5.34	5.2	V
V_{OL}	Maximum Low Level Output Voltage	$V_{IN}=V_{IH}$ or V_{IL} $\|I_{OUT}\|\leq 20\ \mu A$	2.0V	0	0.1	0.1	0.1	V
			4.5V	0	0.1	0.1	0.1	V
			6.0V	0	0.1	0.1	0.1	V
		$V_{IN}=V_{IH}$ or V_{IL} $\|I_{OUT}\|\leq 6.0$ mA	4.5V	0.2	0.26	0.33	0.4	V
		$\|I_{OUT}\|\leq 7.8$ mA	6.0V	0.2	0.26	0.33	0.4	V
I_{IN}	Maximum Input Current	$V_{IN}=V_{CC}$ or GND	6.0V		±0.1	±1.0	±1.0	μA
I_{OZ}	Maximum TRI-STATE Output Leakage Current	$V_{OUT}=V_{CC}$ or GND $OC=V_{IH}$	6.0V		±0.5	±5.0	±10	μA
I_{CC}	Maximum Quiescent Supply Current	$V_{IN}=V_{CC}$ or GND $I_{OUT}=0\ \mu A$	6.0V		8.0	80	160	μA

Note 1: Absolute Maximum Ratings are those values beyond which damage to the device may occur.

Note 2: Unless otherwise specified all voltages are referenced to ground.

Note 3: Power Dissipation temperature derating — plastic "N" package: −12 mW/°C from 65°C to 85°C; ceramic "J" package: −12 mW/°C from 100°C to 125°C.

Note 4: For a power supply of 5V ±10% the worst-case output voltages (V_{OH}, and V_{OL}) occur for HC at 4.5V. Thus the 4.5V values should be used when designing with this supply. Worst-case V_{IH} and V_{IL} occur at $V_{CC}=5.5$V and 4.5V respectively. (The V_{IH} value at 5.5V is 3.85V.) The worst-case leakage current (I_{IN}, I_{CC}, and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0V values should be used.

**V_{IL} limits are currently tested at 20% of V_{CC}. The above V_{IL} specification (30% of V_{CC}) will be implemented no later than Q1, CY'89.

AC Electrical Characteristics $V_{CC}=5V$, $T_A=25°C$, $t_r=t_f=6$ ns

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Symbol	Parameter	Conditions	Typ	Guaranteed Limit	Units
t_{PHL}, t_{PLH}	Maximum Propagation Delay, Data to Q	$C_L=45$ pF	12	19	ns
t_{PHL}, t_{PLH}	Maximum Propagation Delay, LE to Q	$C_L=45$ pF	12	20	ns
t_{PZH}, t_{PZL}	Maximum Output Enable Time	$R_L=1$ kΩ $C_L=45$ pF	13	25	ns
t_{PHZ}, t_{PLZ}	Maximum Output Disable Time	$R_L=1$ kΩ $C_L=5$ pF	11	20	ns
t_S	Minimum Set Up Time, Data to LE		10	15	ns
t_H	Minimum Hold Time, LE to Data		2	5	ns
t_W	Minimum Pulse Width, LE or Data		10	16	ns

AC Electrical Characteristics

Symbol	Parameter	Conditions	V_{CC}	$T_A=25°C$		74HC $T_A=-40$ to 85°C	54HC $T_A=-55$ to 125°C	Units
				Typ	Guaranteed Limits			
t_{PHL}, t_{PLH}	Maximum Propagation Delay Data to Q	$C_L=50$ pF	2.0V	45	110	138	165	ns
		$C_L=150$ pF	2.0V	58	150	188	225	ns
		$C_L=50$ pF	4.5V	14	22	28	33	ns
		$C_L=150$ pF	4.5V	21	30	38	40	ns
		$C_L=50$ pF	6.0V	12	19	24	29	ns
		$C_L=150$ pF	6.0V	19	26	33	39	ns
t_{PHL}, t_{PLH}	Maximum Propagation Delay, Latch Enable to Q	$C_L=50$ pF	2.0V	46	115	143	173	ns
		$C_L=150$ pF	2.0V	60	155	194	233	ns
		$C_L=50$ pF	4.5V	14	23	29	35	ns
		$C_L=150$ pF	4.5V	21	31	47	47	ns
		$C_L=50$ pF	6.0V	12	20	25	30	ns
		$C_L=150$ pF	6.0V	19	27	34	41	ns
t_{PZH}, t_{PZL}	Maximum Output Enable Time	$R_L=1$ kΩ						
		$C_L=50$ pF	2.0V	55	140	175	210	ns
		$C_L=150$ pF	2.0V	67	180	225	270	ns
		$C_L=50$ pF	4.5V	15	28	35	42	ns
		$C_L=150$ pF	4.5V	24	36	45	54	ns
		$C_L=50$ pF	6.0V	14	24	30	36	ns
		$C_L=150$ pF	6.0V	22	31	39	47	ns
t_{PHZ}, t_{PLZ}	Maximum Output Disable Time	$R_L=1$ kΩ $C_L=50$ pF	2.0V	40	125	156	188	ns
			4.5V	13	25	31	38	ns
			6.0V	12	21	27	32	ns
t_S	Minimum Set Up Time Data to LE		2.0V	30	75	95	110	ns
			4.5V	10	15	19	22	ns
			6.0V	9	13	16	19	ns
t_H	Minimum Hold Time LE to Data		2.0V		25	31	38	ns
			4.5V		5	6	7	ns
			6.0V		4	5	6	ns
t_W	Minimum Pulse Width LE, or Data		2.0V	30	80	100	120	ns
			4.5V	9	16	20	24	ns
			6.0V	8	14	18	20	ns
t_{TLH}, t_{THL}	Maximum Output Rise and Fall Time, Clock	$C_L=50$ pF	2.0V	25	60	75	90	ns
			4.5V	7	12	15	18	ns
			6.0V	6	10	13	15	ns
C_{PD}	Power Dissipation Capacitance (Note 5) (per latch)	$OC=V_{CC}$		30				pF
		$OC=GND$		50				pF
C_{IN}	Maximum Input Capacitance			5	10	10	10	pF
C_{OUT}	Maximum Output Capacitance			15	20	20	20	pF

Note 5: C_{PD} determines the no load dynamic power consumption, $P_D=C_{PD} V_{CC}^2 f+I_{CC} V_{CC}$, and the no load dynamic current consumption, $I_S=C_{PD} V_{CC} f+I_{CC}$.